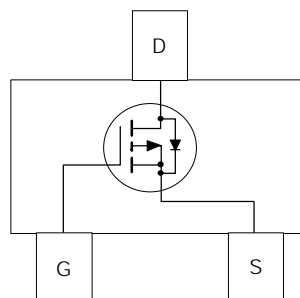
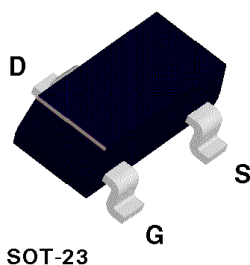


**NDS0605****P-Channel Enhancement Mode Field Effect Transistor****General Description**

These P-Channel enhancement mode power field effect transistors are produced using National's proprietary, high cell density, DMOS technology. This very high density process has been designed to minimize on-state resistance, provide rugged and reliable performance and fast switching. They can be used, with a minimum of effort, in most applications requiring up to 0.18A DC and can deliver pulsed currents up to 1A. This product is particularly suited to low voltage applications requiring a low current high side switch.

**Features**

- -0.18A, -60V.  $R_{DS(ON)} = 5\Omega$  @  $V_{GS} = -10V$ .
- Voltage controlled p-channel small signal switch.
- High density cell design for low  $R_{DS(ON)}$ .
- High saturation current.

**Absolute Maximum Ratings**  $T_A = 25^\circ\text{C}$  unless otherwise noted

Symbol	Parameter	NDS0605	Units
$V_{DSS}$	Drain-Source Voltage	-60	V
$V_{DGR}$	Drain-Gate Voltage ( $R_{GS} \leq 1\text{ M}\Omega$ )	-60	V
$V_{GSS}$	Gate-Source Voltage - Continuous	$\pm 20$	V
$I_D$	Drain Current - Continuous	-0.18	A
	- Pulsed	-1	
$P_D$	Maximum Power Dissipation $T_A = 25^\circ\text{C}$	0.36	W
	Derate above $25^\circ\text{C}$	2.9	mW/ $^\circ\text{C}$
$T_J, T_{STG}$	Operating and Storage Temperature Range	-55 to 150	$^\circ\text{C}$
$T_L$	Maximum lead temperature for soldering purposes, 1/16" from case for 10 seconds	300	$^\circ\text{C}$

**THERMAL CHARACTERISTICS**

$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient	350	$^\circ\text{C}/\text{W}$
-----------------	---	-----	---------------------------

**ELECTRICAL CHARACTERISTICS** ( $T_A = 25^\circ\text{C}$  unless otherwise noted)

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>OFF CHARACTERISTICS</b>						
$BV_{DSS}$	Drain-Source Breakdown Voltage	$V_{GS} = 0\text{ V}, I_D = -10\ \mu\text{A}$	-60			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS} = -48\text{ V}, V_{GS} = 0\text{ V}$			-1	$\mu\text{A}$
			$T_J = 125^\circ\text{C}$			-500
$I_{GSSF}$	Gate - Body Leakage, Forward	$V_{GS} = 20\text{ V}, V_{DS} = 0\text{ V}$			100	nA
$I_{GSSR}$	Gate - Body Leakage, Reverse	$V_{GS} = -20\text{ V}, V_{DS} = 0\text{ V}$			-100	nA
<b>ON CHARACTERISTICS</b> (Note 1)						
$V_{GS(th)}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$	-1		-3	V
			$T_J = 125^\circ\text{C}$	-0.6		-2.8
$R_{DS(on)}$	Static Drain-Source On-Resistance	$V_{GS} = -10\text{ V}, I_D = -0.5\text{ A}$			5	$\Omega$
			$T_J = 125^\circ\text{C}$			10
		$V_{GS} = -4.5\text{ V}, I_D = -0.25\text{ A}$			7.5	
			$T_J = 125^\circ\text{C}$			15
$I_{D(on)}$	On-State Drain Current	$V_{GS} = -10\text{ V}, V_{DS} = -10\text{ V}$	-0.6			A
		$V_{GS} = -4.5\text{ V}, V_{DS} = -10\text{ V}$	-0.25			
$g_{FS}$	Forward Transconductance	$V_{DS} = -10\text{ V}, I_D = -0.2\text{ A}$	0.07			S
<b>DYNAMIC CHARACTERISTICS</b>						
$C_{iss}$	Input Capacitance	$V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V},$ $f = 1.0\text{ MHz}$			60	pF
$C_{oss}$	Output Capacitance				25	pF
$C_{rss}$	Reverse Transfer Capacitance				5	pF
<b>SWITCHING CHARACTERISTICS</b> (Note 1)						
$t_{D(on)}$	Turn - On Delay Time	$V_{DD} = -30\text{ V}, I_D = -0.2\text{ A},$ $V_{GS} = -10\text{ V}, R_{GEN} = 25\ \Omega$			10	nS
$t_T$	Turn - On Rise Time				15	nS
$t_{D(off)}$	Turn - Off Delay Time				15	nS
$t_f$	Turn - Off Fall Time				20	nS
<b>DRAIN-SOURCE DIODE CHARACTERISTICS</b>						
$I_S$	Continuous Source Diode Current				-0.18	A
$I_{SM}$	Maximum Pulsed Source Diode Current (Note 1)				-1	A
$V_{SD}$	Drain-Source Diode Forward Voltage	$V_{GS} = 0\text{ V}, I_S = -0.5\text{ A}$ (Note 1)			-1.5	V
			$T_J = 125^\circ\text{C}$			-1.3

Note :

 1. Pulse Test: Pulse Width  $\leq 300\ \mu\text{s}$ , Duty Cycle  $\leq 2.0\%$ .

# Typical Electrical Characteristics

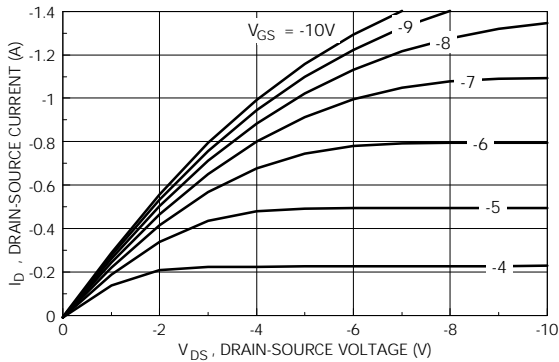


Figure 1. On-Region Characteristics

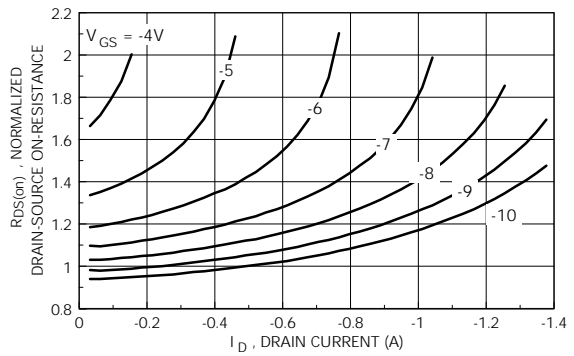


Figure 2. On-Resistance Variation with Gate Voltage and Drain Current

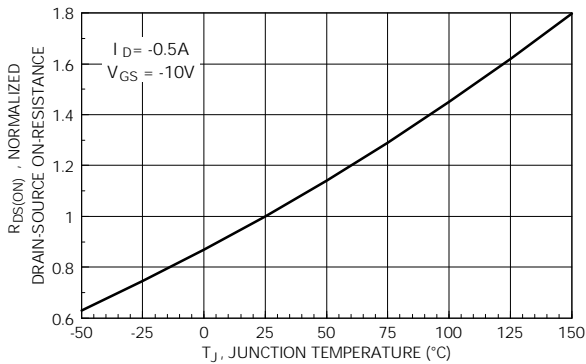


Figure 3. On-Resistance Variation with Temperature

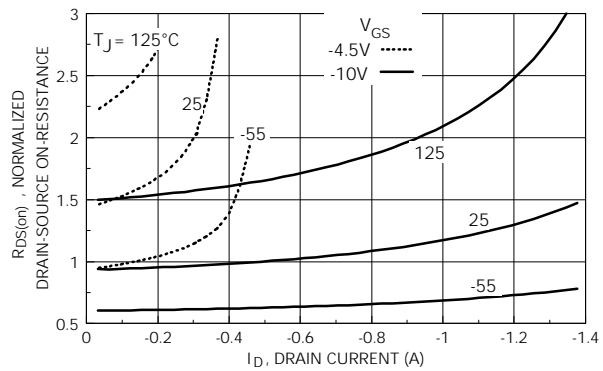


Figure 4. On-Resistance Variation with Drain Current and Temperature

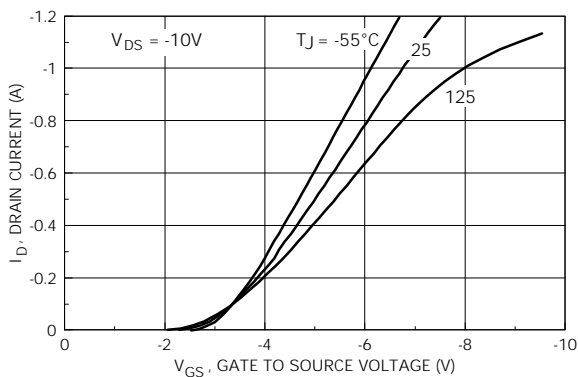


Figure 5. Transfer Characteristics

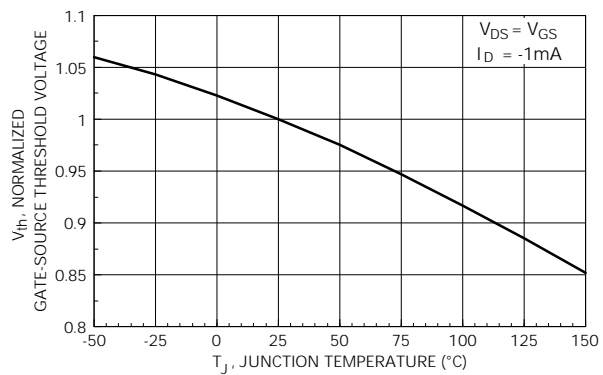
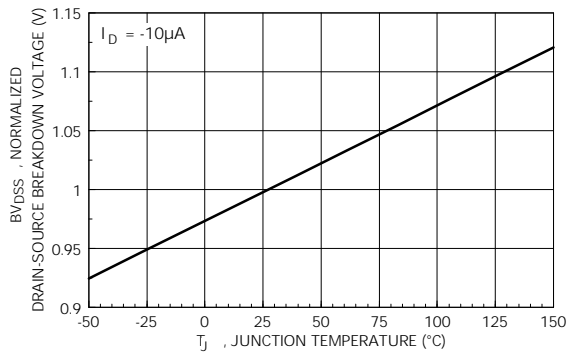
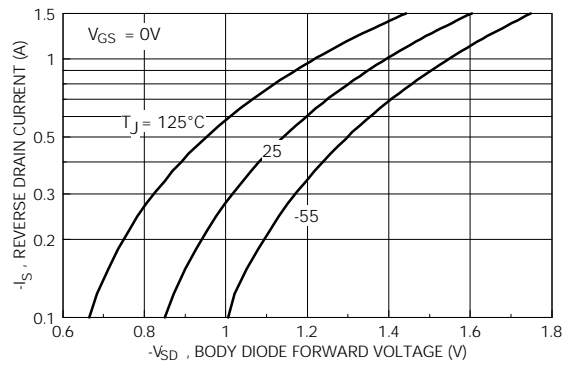


Figure 6. Gate Threshold Variation with Temperature

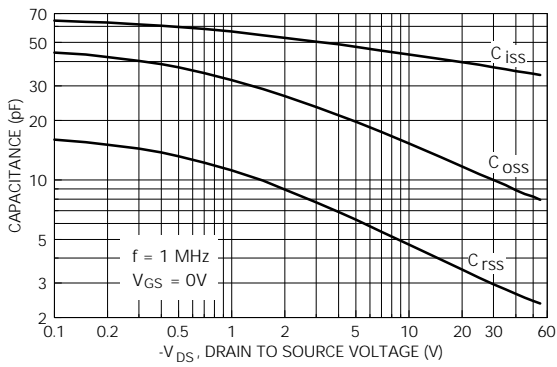
## Typical Electrical Characteristics (continued)



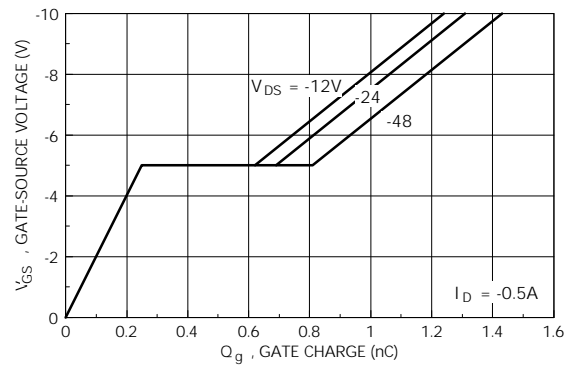
**Figure 7. Breakdown Voltage Variation with Temperature**



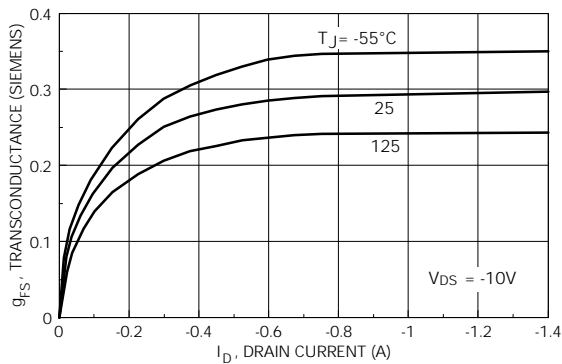
**Figure 8. Body Diode Forward Voltage Variation with Current and Temperature**



**Figure 9. Capacitance Characteristics**



**Figure 10. Gate Charge Characteristics**



**Figure 11. Transconductance Variation with Drain Current and Temperature**

## Typical Electrical Characteristics (continued)

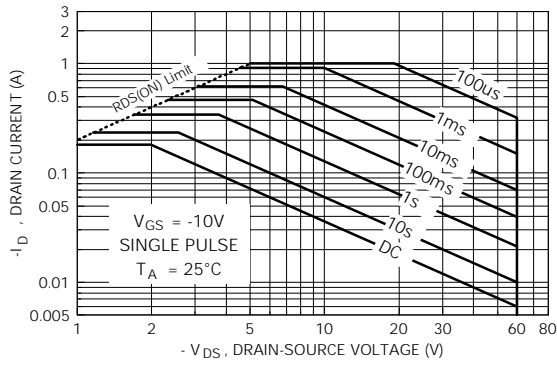


Figure 12. Maximum Safe Operating Area

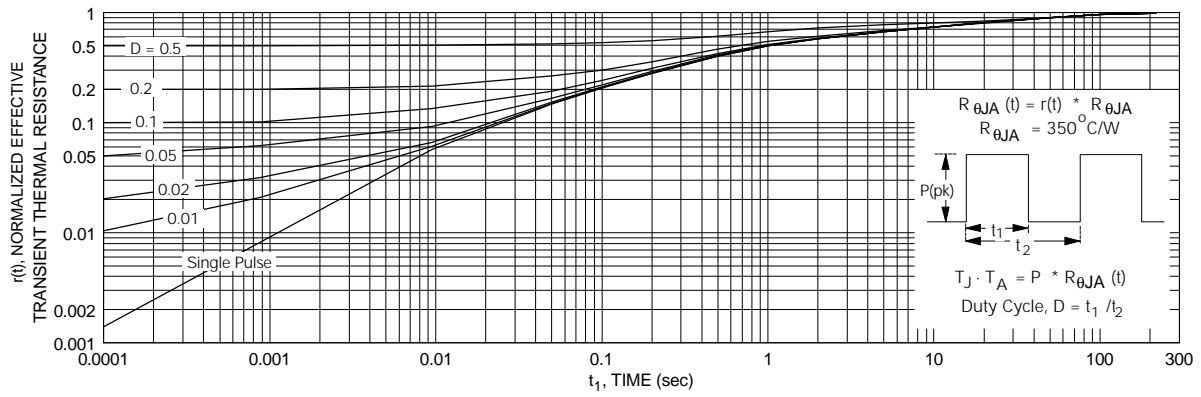


Figure 13. Transient Thermal Response Curve.